



04-19-02

OKCO  
Attorney's Docket No.: 09712-055001 / Z-200  
B3C0  
*XIA*

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Peter de Groot

Art Unit : Unknown

Serial No. : 10/025,595

Examiner : Unknown

Filed : December 18, 2001

Title : OPTICAL SURFACE PROFILING SYSTEMS

Commissioner for Patents  
Washington, D.C. 20231INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449, copies of which are enclosed.

This statement is being filed before the receipt of a first Office action on the merits.

Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: March 22, 2002

Eric L. Prahl  
Reg. No. 32,590

Fish & Richardson P.C.  
225 Franklin Street  
Boston, Massachusetts 02110-2804  
Telephone: (617) 542-5070  
Facsimile: (617) 542-8906

20408007.doc

## CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, Washington, D.C. 20231.

March 25, 2002  
Date of Deposit

Vasilia Kelly  
Signature

Vasilia Kelly  
Typed or Printed Name of Person Signing Certificate

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-055001	Application No. 10/025,595
<b>Information Disclosure Statement</b> <b>by Applicant</b> <small>(Use several sheets if necessary)</small> <small>(37 CFR §1.98(b))</small>		Applicant Peter de Groot	
		Filing Date December 18, 2001	Group Art Unit

<b>U.S. Patent Documents</b>							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,340,306	07/20/82	Balasubramanian			
	AB	4,869,593	09/26/89	Biegen			
	AC	5,239,178	08/24/93	Derndinger et al.			
	AD	5,398,113	03/14/95	de Groot			
	AE	5,737,084	04/07/98	Ishihara			

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
	AF						

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>		
Examiner Initial	Desig. ID	Document
	AG	Caber, Paul J., "Interferometric Profiler for Rough Surfaces", <i>Applied Optics</i> , Vol. 32, No. 19, July 1, 1993, pp. 3438-3441
	AH	Dresel, Thomas et al., "Three-dimensional sensing of rough surfaces by coherence radar", <i>Applied Optics</i> , Vol. 31, No. 7, March 1, 1992, pp. 919-925
	AI	Tiziani H.J. et al., "Chromatic confocal microscopy with microlenses", <i>Journal of Modern Optics</i> , Vol. 43, No. 1, 1996, pp. 155-163
	AJ	Tiziani H.J. et al., "Three-dimensional analysis by a microlens-array confocal arrangement", <i>Applied Optics</i> , Vol. 33, No. 4, February 1, 1994, pp. 567-572

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	